Search Notes

Application/Control No.

Applicant(s)/Patent under Reexamination

OGAWA, HIDEHIKO
Art Unit

10/767,726 Examiner

Thomas D. Lee

2625

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Class	Subclass	Date	Examiner
358	1.15, 402, 440	9/22/2006	TDL
379	100.01	9/22/2006	TDL
379	100.08	9/22/2006	TDL
379	100.13	9/22/2006	TDL
379	100.17	9/22/2006	TDL
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updated		3/14/2007	TDL
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